

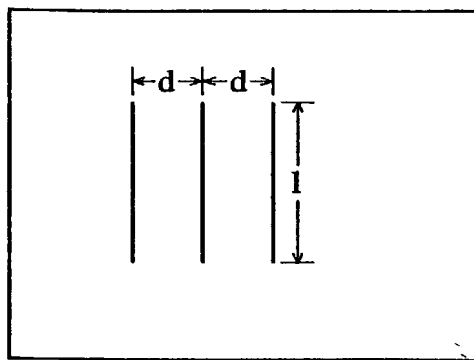
Title: AN ELECTRON BEAM DEVICE AND METHOD FOR STEREOSCOPIC MEASUREMENTS

Inventor(s): Nobuo KOCHI et al.

Appl. No.: 10/086,625

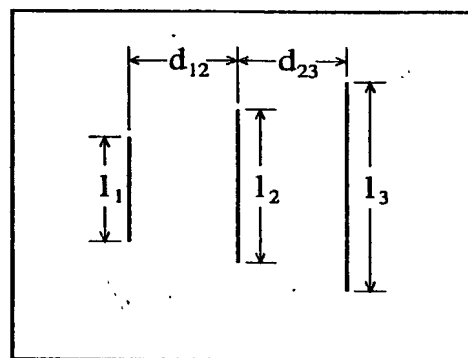
1/12

FIG.1 (A)



0 degree

FIG.1 (B)



10 degrees

FIG.2 (A)

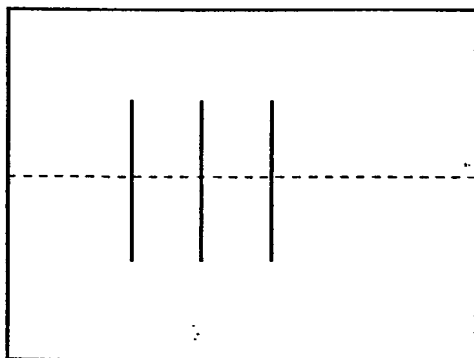
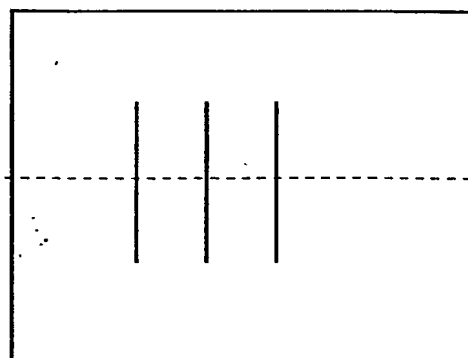


FIG.2 (B)



Epipolar line

FIG.3

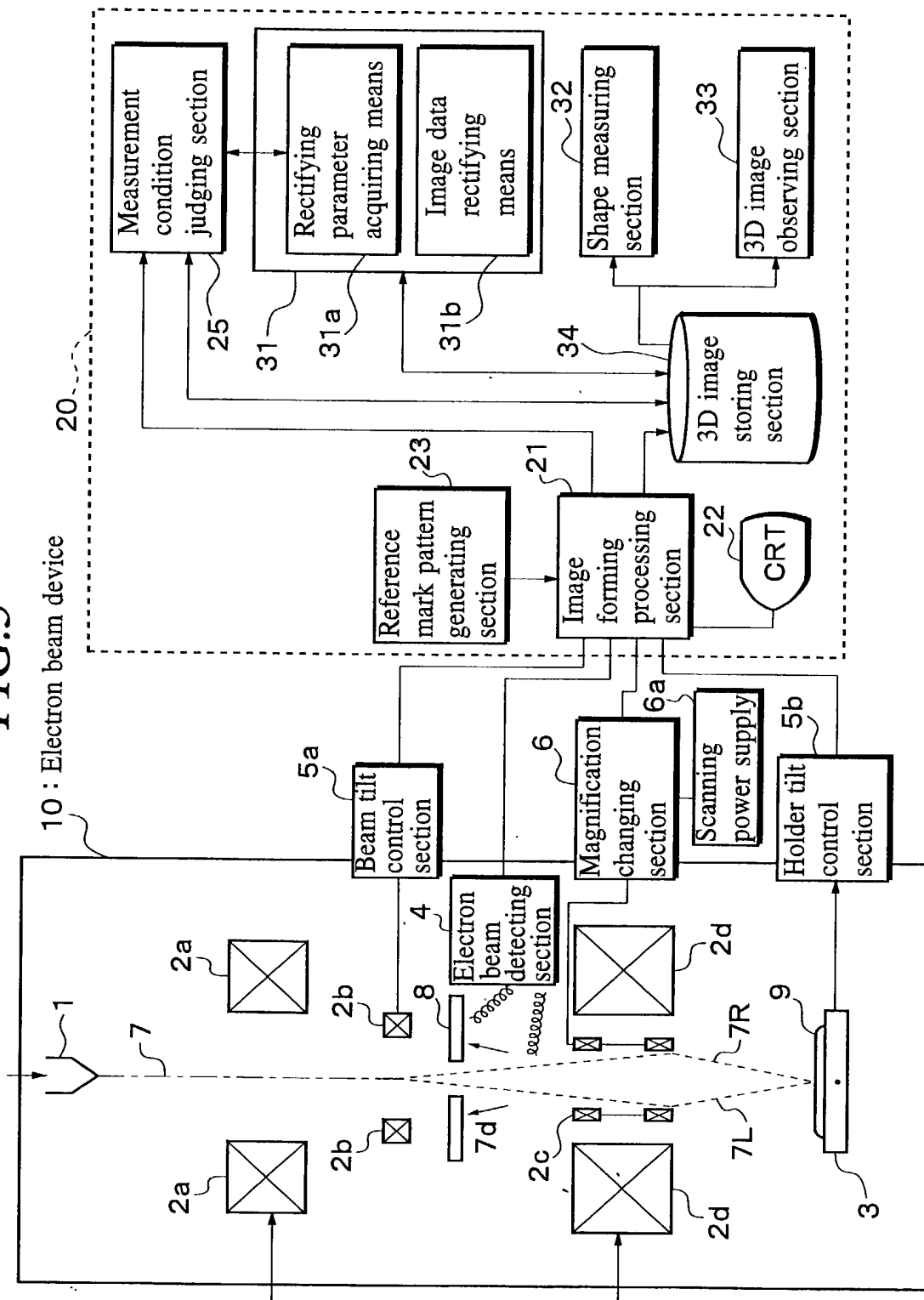


FIG.4 (A)

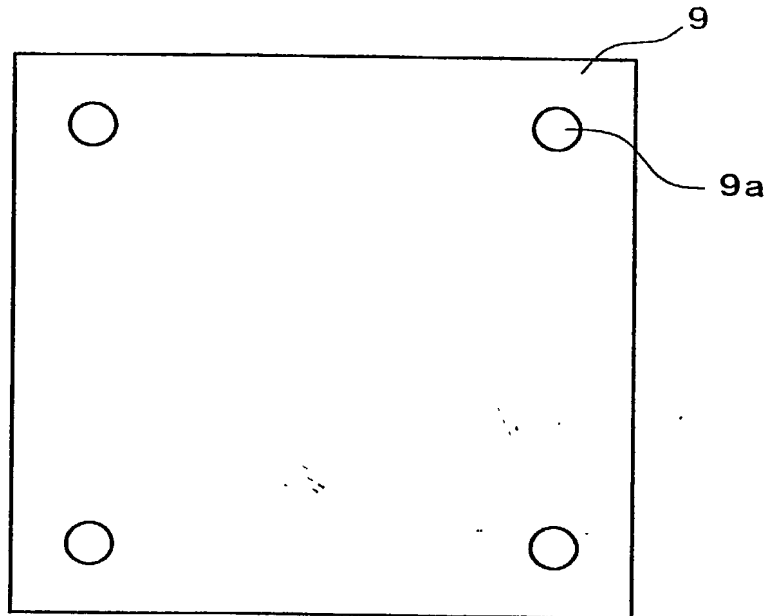


FIG.4 (B)

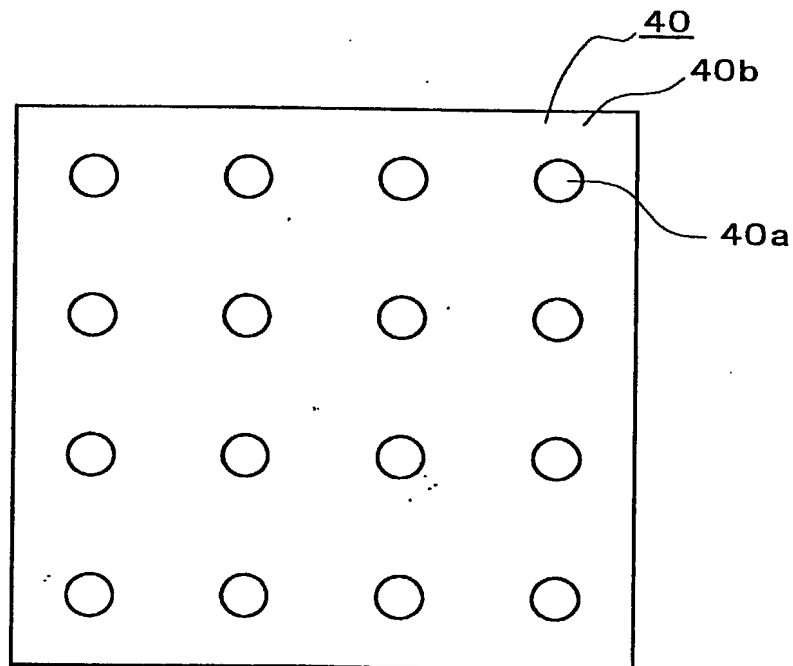
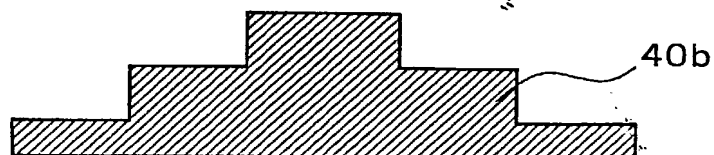
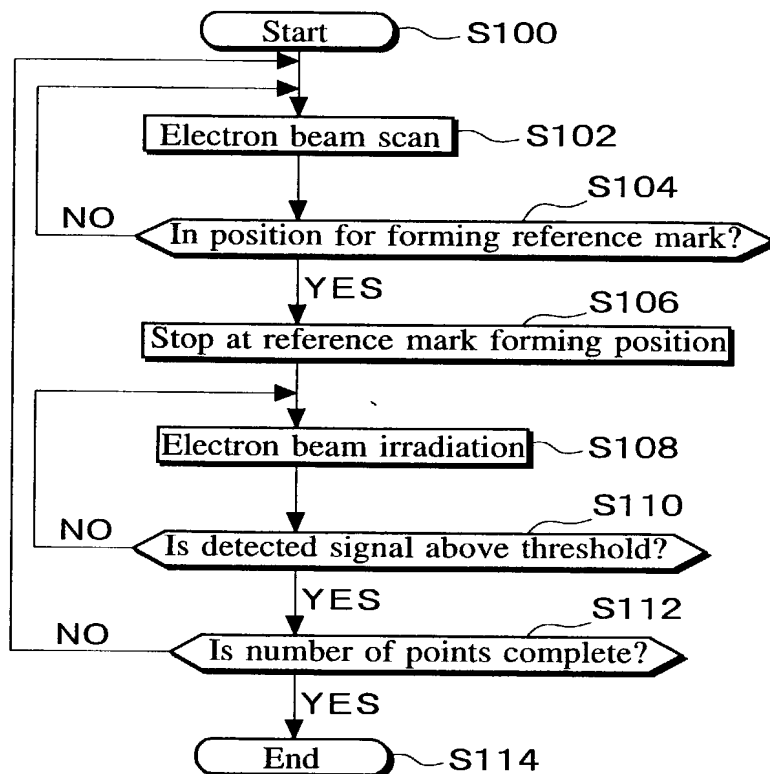


FIG.4 (C)



4/12

FIG.5



5/12

FIG.6

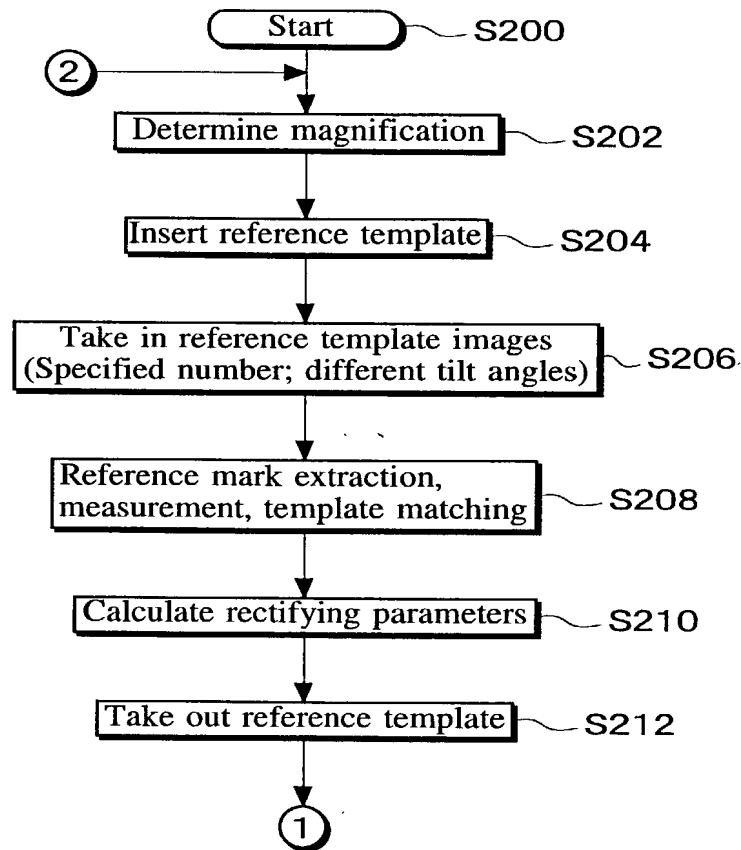
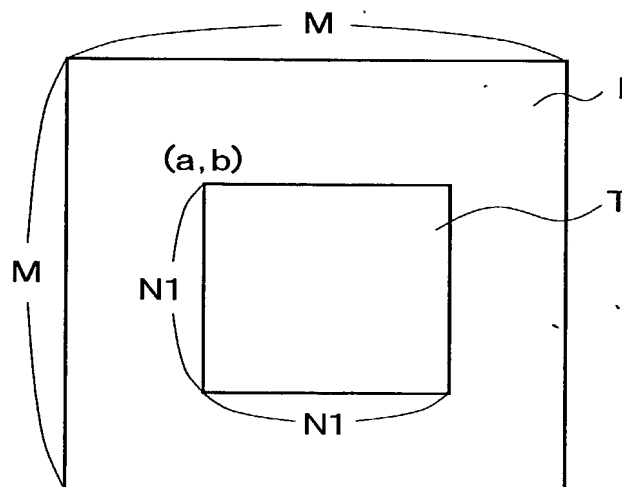


FIG.7

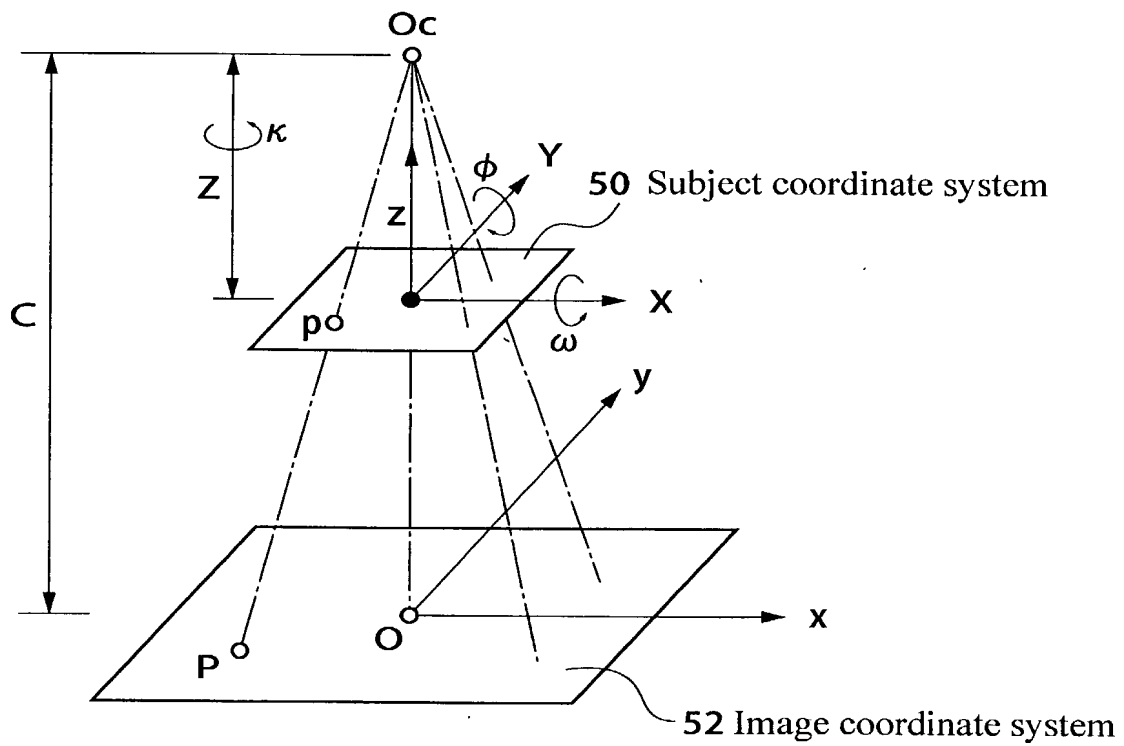


Title: AN ELECTRON BEAM DEVICE  
AND METHOD FOR STEREOSCOPIC  
MEASUREMENTS

Inventor(s): Nobuo KOCHI et al.  
Appl. No.: 10/086,625

6/12

FIG. 8

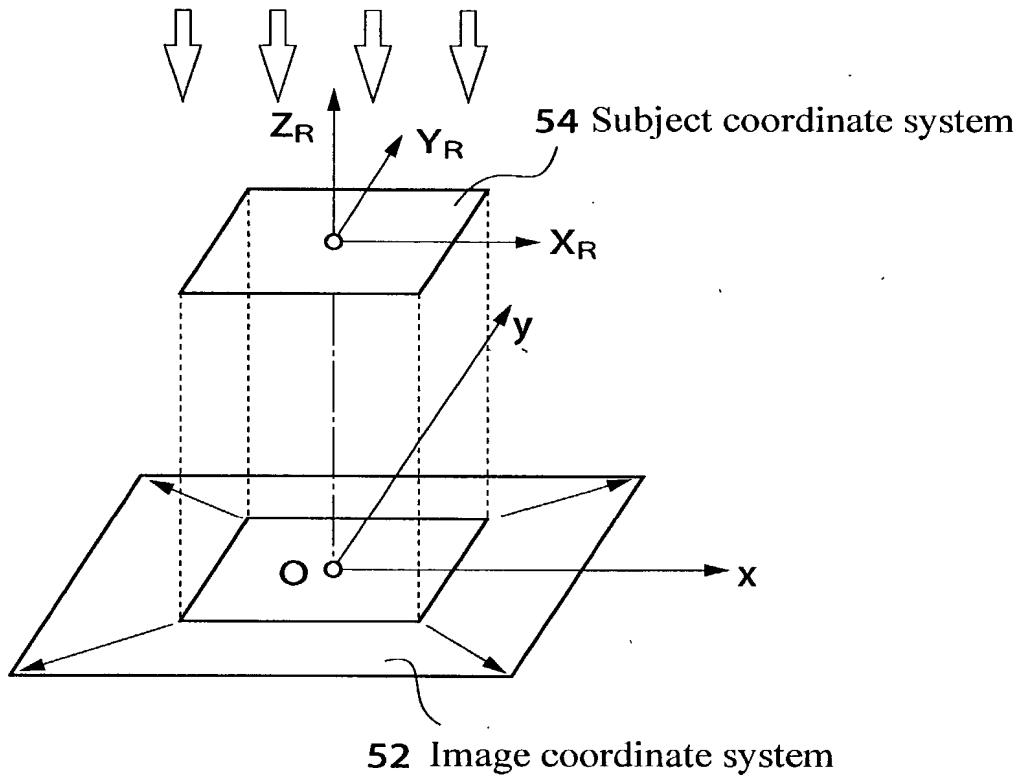


Title: AN ELECTRON BEAM DEVICE  
AND METHOD FOR STEREOSCOPIC  
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Appl. No.: 10/086,625

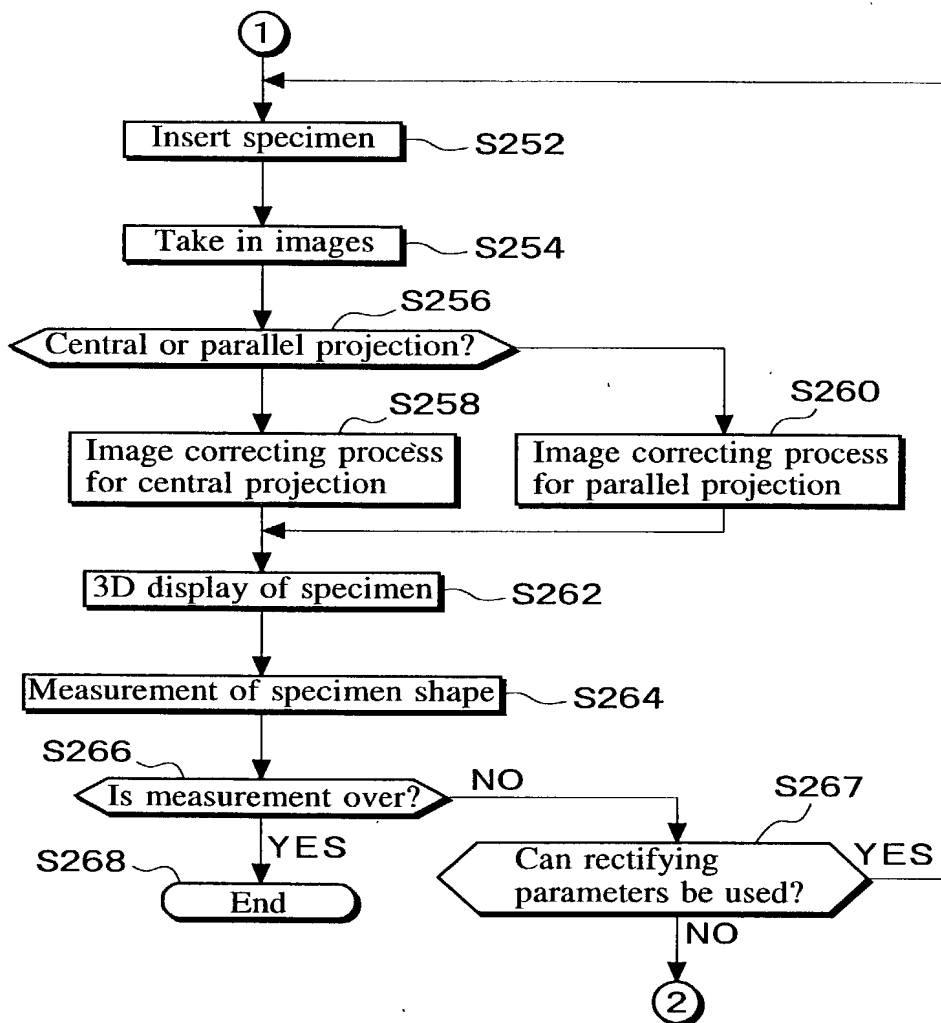
7/12

**FIG. 9**



8/12

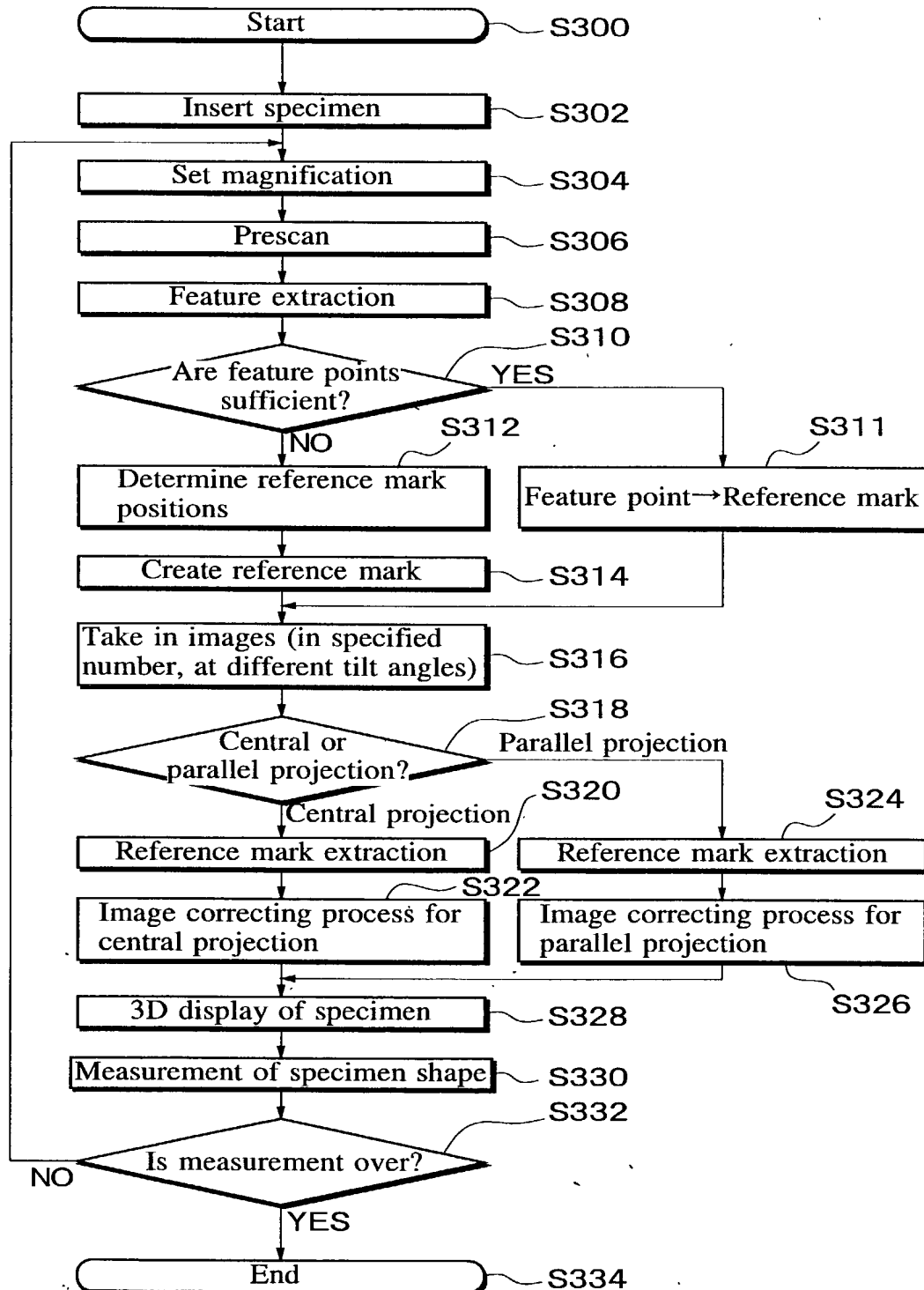
FIG. 10





9/12

FIG.11



Title: AN ELECTRON BEAM DEVICE AND METHOD FOR STEREOSCOPIC MEASUREMENTS

Inventor(s): Nobuo KOCHI et al.

Appl. No.: 10/086,625

10/12

FIG.12 (A)

Laplacean operator

0	-1	0
-1	5	-1
0	-1	0

FIG.12 (B)

Line detecting operator

-1/2	1	-1/2
-1/2	1	-1/2
-1/2	1	-1/2

FIG.13

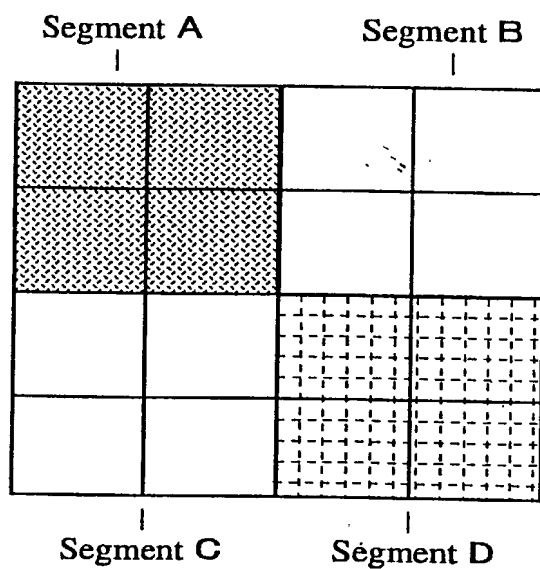


FIG.14

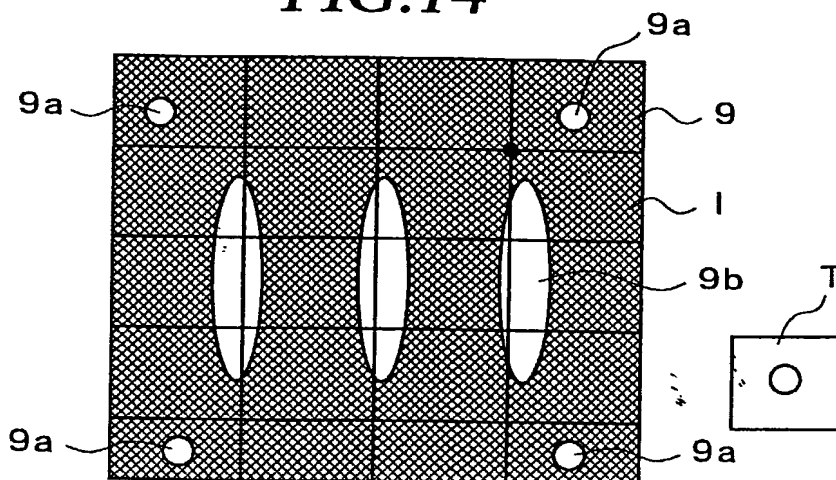


FIG.15

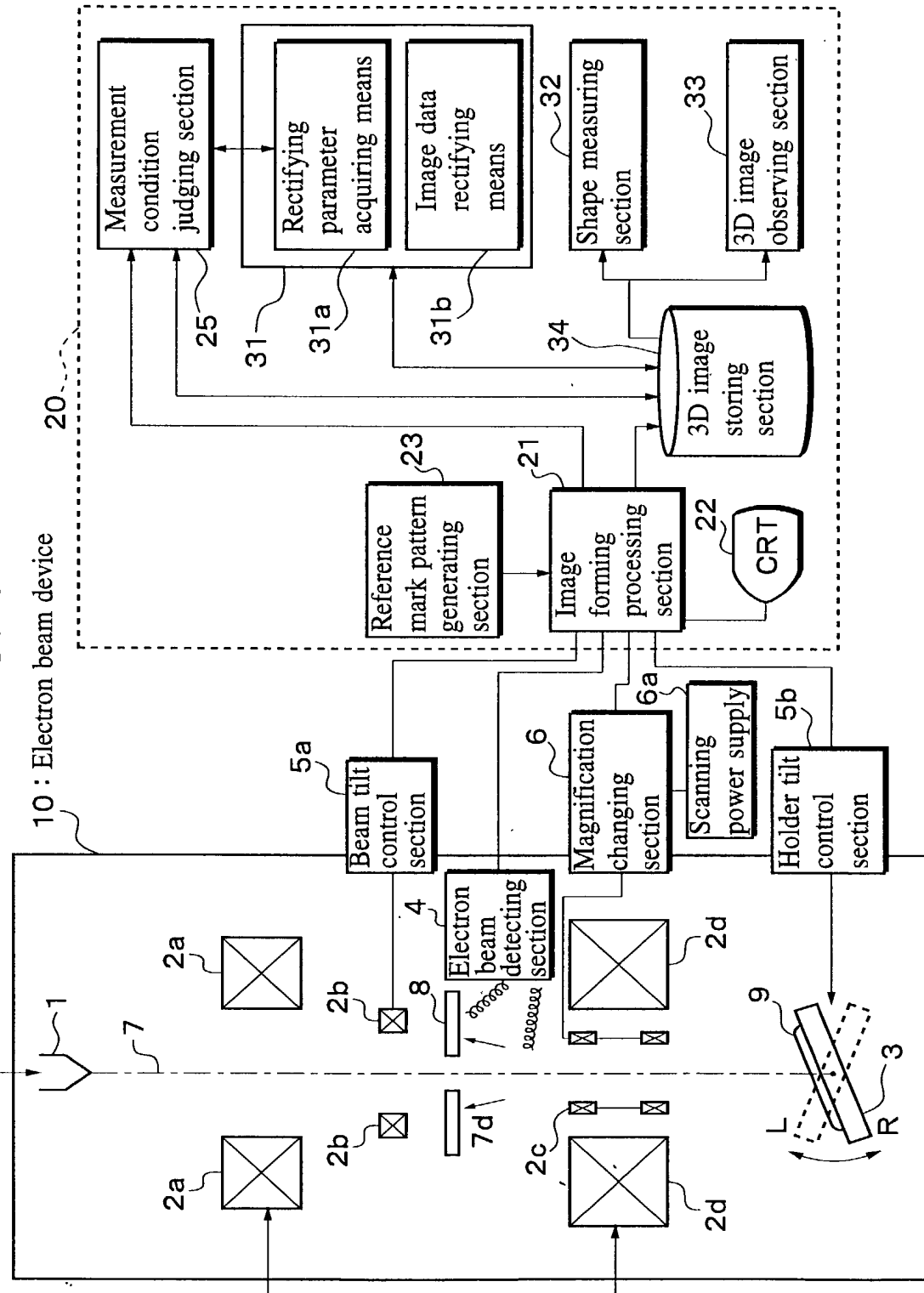


FIG.16

